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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	185000
Number of Logic Elements/Cells	490000
Total RAM Bits	41984000
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1760-BBGA, FCBGA
Supplier Device Package	1760-FCBGA (42.5x42.5)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/5sgxeb5r3f43i3n">https://www.e-xfl.com/product-detail/intel/5sgxeb5r3f43i3n</a>

**Table 1. Stratix V GX and GS Commercial and Industrial Speed Grade Offering <sup>(1), (2), (3)</sup> (Part 2 of 2)**

Transceiver Speed Grade	Core Speed Grade							
	C1	C2, C2L	C3	C4	I2, I2L	I3, I3L	I3YY	I4
3 GX channel—8.5 Gbps	—	Yes	Yes	Yes	—	Yes	Yes <sup>(4)</sup>	Yes

**Notes to Table 1:**

- (1) C = Commercial temperature grade; I = Industrial temperature grade.  
 (2) Lower number refers to faster speed grade.  
 (3) C2L, I2L, and I3L speed grades are for low-power devices.  
 (4) I3YY speed grades can achieve up to 10.3125 Gbps.

Table 2 lists the industrial and commercial speed grades for the Stratix V GT devices.

**Table 2. Stratix V GT Commercial and Industrial Speed Grade Offering <sup>(1), (2)</sup>**

Transceiver Speed Grade	Core Speed Grade			
	C1	C2	I2	I3
2 GX channel—12.5 Gbps GT channel—28.05 Gbps	Yes	Yes	—	—
3 GX channel—12.5 Gbps GT channel—25.78 Gbps	Yes	Yes	Yes	Yes

**Notes to Table 2:**

- (1) C = Commercial temperature grade; I = Industrial temperature grade.  
 (2) Lower number refers to faster speed grade.

**Absolute Maximum Ratings**

Absolute maximum ratings define the maximum operating conditions for Stratix V devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.



Conditions other than those listed in Table 3 may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

**Table 3. Absolute Maximum Ratings for Stratix V Devices (Part 1 of 2)**

Symbol	Description	Minimum	Maximum	Unit
V <sub>CC</sub>	Power supply for core voltage and periphery circuitry	−0.5	1.35	V
V <sub>CCPT</sub>	Power supply for programmable power technology	−0.5	1.8	V
V <sub>CCPGM</sub>	Power supply for configuration pins	−0.5	3.9	V
V <sub>CC_AUX</sub>	Auxiliary supply for the programmable power technology	−0.5	3.4	V
V <sub>CCBAT</sub>	Battery back-up power supply for design security volatile key register	−0.5	3.9	V
V <sub>CCPD</sub>	I/O pre-driver power supply	−0.5	3.9	V
V <sub>CCIO</sub>	I/O power supply	−0.5	3.9	V

**Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 2 of 2)**

Symbol	Description	Conditions	Resistance Tolerance				Unit
			C1	C2, I2	C3, I3, I3YY	C4, I4	
50-Ω R <sub>S</sub>	Internal series termination without calibration (50-Ω setting)	V <sub>CCIO</sub> = 1.8 and 1.5 V	±30	±30	±40	±40	%
50-Ω R <sub>S</sub>	Internal series termination without calibration (50-Ω setting)	V <sub>CCIO</sub> = 1.2 V	±35	±35	±50	±50	%
100-Ω R <sub>D</sub>	Internal differential termination (100-Ω setting)	V <sub>CCPD</sub> = 2.5 V	±25	±25	±25	±25	%

Calibration accuracy for the calibrated series and parallel OCTs are applicable at the moment of calibration. When voltage and temperature conditions change after calibration, the tolerance may change.

OCT calibration is automatically performed at power-up for OCT-enabled I/Os. Table 13 lists the OCT variation with temperature and voltage after power-up calibration. Use Table 13 to determine the OCT variation after power-up calibration and Equation 1 to determine the OCT variation without recalibration.

**Equation 1. OCT Variation Without Recalibration for Stratix V Devices <sup>(1), (2), (3), (4), (5), (6)</sup>**

$$R_{OCT} = R_{SCAL} \left( 1 + \left\langle \frac{dR}{dT} \times \Delta T \right\rangle \pm \left\langle \frac{dR}{dV} \times \Delta V \right\rangle \right)$$

**Notes to Equation 1:**

- (1) The R<sub>OCT</sub> value shows the range of OCT resistance with the variation of temperature and V<sub>CCIO</sub>.
- (2) R<sub>SCAL</sub> is the OCT resistance value at power-up.
- (3) ΔT is the variation of temperature with respect to the temperature at power-up.
- (4) ΔV is the variation of voltage with respect to the V<sub>CCIO</sub> at power-up.
- (5) dR/dT is the percentage change of R<sub>SCAL</sub> with temperature.
- (6) dR/dV is the percentage change of R<sub>SCAL</sub> with voltage.

Table 13 lists the on-chip termination variation after power-up calibration.

**Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 1 of 2) <sup>(1)</sup>**

Symbol	Description	V <sub>CCIO</sub> (V)	Typical	Unit
dR/dV	OCT variation with voltage without recalibration	3.0	0.0297	% / mV
		2.5	0.0344	
		1.8	0.0499	
		1.5	0.0744	
		1.2	0.1241	

**Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 6 of 7)**

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Inter-transceiver block transmitter channel-to- channel skew	xN PMA bonded mode	—	—	500	—	—	500	—	—	500	ps
<b>CMU PLL</b>											
Supported Data Range	—	600	—	12500	600	—	12500	600	—	8500/ 10312.5 <sup>(24)</sup>	Mbps
t <sub>pll_powerdown</sub> <sup>(15)</sup>	—	1	—	—	1	—	—	1	—	—	μs
t <sub>pll_lock</sub> <sup>(16)</sup>	—	—	—	10	—	—	10	—	—	10	μs
<b>ATX PLL</b>											
Supported Data Rate Range	VCO post-divider L=2	8000	—	14100	8000	—	12500	8000	—	8500/ 10312.5 <sup>(24)</sup>	Mbps
	L=4	4000	—	7050	4000	—	6600	4000	—	6600	Mbps
	L=8	2000	—	3525	2000	—	3300	2000	—	3300	Mbps
	L=8, Local/Central Clock Divider =2	1000	—	1762.5	1000	—	1762.5	1000	—	1762.5	Mbps
t <sub>pll_powerdown</sub> <sup>(15)</sup>	—	1	—	—	1	—	—	1	—	—	μs
t <sub>pll_lock</sub> <sup>(16)</sup>	—	—	—	10	—	—	10	—	—	10	μs
<b>fPLL</b>											
Supported Data Range	—	600	—	3250/ 3125 <sup>(25)</sup>	600	—	3250/ 3125 <sup>(25)</sup>	600	—	3250/ 3125 <sup>(25)</sup>	Mbps
t <sub>pll_powerdown</sub> <sup>(15)</sup>	—	1	—	—	1	—	—	1	—	—	μs

Figure 2 shows the differential transmitter output waveform.

**Figure 2. Differential Transmitter Output Waveform**

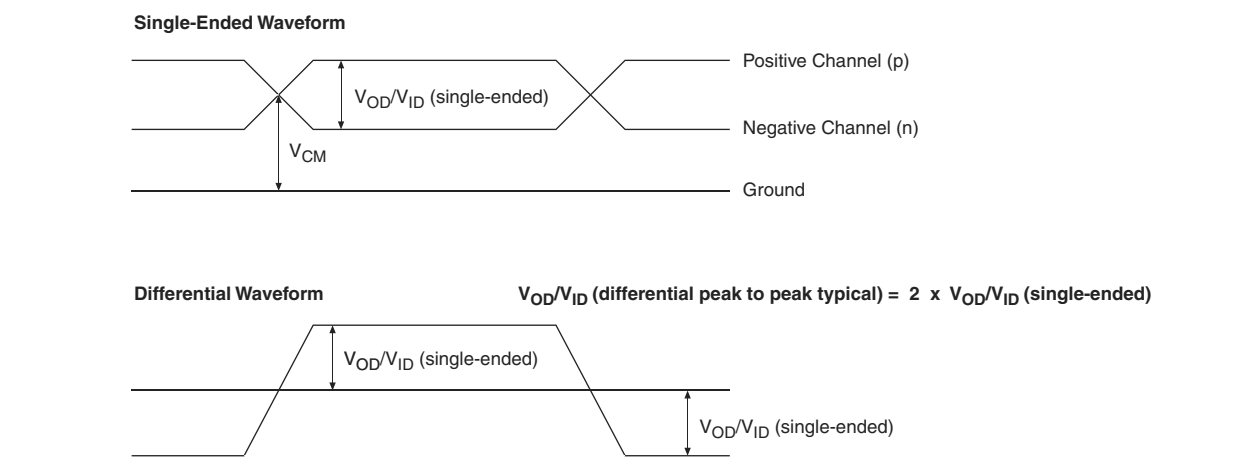


Figure 3 shows the Stratix V AC gain curves for GX channels.

**Figure 3. AC Gain Curves for GX Channels (full bandwidth)**



Stratix V GT devices contain both GX and GT channels. All transceiver specifications for the GX channels not listed in Table 28 are the same as those listed in Table 23.

Table 28 lists the Stratix V GT transceiver specifications.

- XFI
- ASI
- HiGig/HiGig+
- HiGig2/HiGig2+
- Serial Data Converter (SDC)
- GPON
- SDI
- SONET
- Fibre Channel (FC)
- PCIe
- QPI
- SFF-8431

Download the Stratix V Characterization Report Tool to view the characterization report summary for these protocols.

## Core Performance Specifications

This section describes the clock tree, phase-locked loop (PLL), digital signal processing (DSP), memory blocks, configuration, and JTAG specifications.

### Clock Tree Specifications

Table 30 lists the clock tree specifications for Stratix V devices.

**Table 30. Clock Tree Performance for Stratix V Devices <sup>(1)</sup>**

Symbol	Performance			Unit
	C1, C2, C2L, I2, and I2L	C3, I3, I3L, and I3YY	C4, I4	
Global and Regional Clock	717	650	580	MHz
Periphery Clock	550	500	500	MHz

**Note to Table 30:**

(1) The Stratix V ES devices are limited to 600 MHz core clock tree performance.

## PLL Specifications

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to 85°C) and the industrial junction temperature range (–40° to 100°C).

**Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)**

Symbol	Parameter	Min	Typ	Max	Unit
$f_{IN}$	Input clock frequency (C1, C2, C2L, I2, and I2L speed grades)	5	—	800 <sup>(1)</sup>	MHz
	Input clock frequency (C3, I3, I3L, and I3YY speed grades)	5	—	800 <sup>(1)</sup>	MHz
	Input clock frequency (C4, I4 speed grades)	5	—	650 <sup>(1)</sup>	MHz
$f_{INPFD}$	Input frequency to the PFD	5	—	325	MHz
$f_{FINPFD}$	Fractional Input clock frequency to the PFD	50	—	160	MHz
$f_{VCO}$ <sup>(9)</sup>	PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades)	600	—	1600	MHz
	PLL VCO operating range (C3, I3, I3L, I3YY speed grades)	600	—	1600	MHz
	PLL VCO operating range (C4, I4 speed grades)	600	—	1300	MHz
$t_{EINDUTY}$	Input clock or external feedback clock input duty cycle	40	—	60	%
$f_{OUT}$	Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades)	—	—	717 <sup>(2)</sup>	MHz
	Output frequency for an internal global or regional clock (C3, I3, I3L speed grades)	—	—	650 <sup>(2)</sup>	MHz
	Output frequency for an internal global or regional clock (C4, I4 speed grades)	—	—	580 <sup>(2)</sup>	MHz
$f_{OUT\_EXT}$	Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades)	—	—	800 <sup>(2)</sup>	MHz
	Output frequency for an external clock output (C3, I3, I3L speed grades)	—	—	667 <sup>(2)</sup>	MHz
	Output frequency for an external clock output (C4, I4 speed grades)	—	—	553 <sup>(2)</sup>	MHz
$t_{OUTDUTY}$	Duty cycle for a dedicated external clock output (when set to 50%)	45	50	55	%
$t_{FCOMP}$	External feedback clock compensation time	—	—	10	ns
$f_{DYCONFIGCLK}$	Dynamic Configuration Clock used for <code>mgmt_clk</code> and <code>scanclk</code>	—	—	100	MHz
$t_{LOCK}$	Time required to lock from the end-of-device configuration or deassertion of <code>areset</code>	—	—	1	ms
$t_{DLOCK}$	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)	—	—	1	ms
$f_{CLBW}$	PLL closed-loop low bandwidth	—	0.3	—	MHz
	PLL closed-loop medium bandwidth	—	1.5	—	MHz
	PLL closed-loop high bandwidth <sup>(7)</sup>	—	4	—	MHz
$t_{PLL\_PSERR}$	Accuracy of PLL phase shift	—	—	±50	ps
$t_{ARESET}$	Minimum pulse width on the <code>areset</code> signal	10	—	—	ns

## Periphery Performance

This section describes periphery performance, including high-speed I/O and external memory interface.

I/O performance supports several system interfaces, such as the **LVDS** high-speed I/O interface, external memory interface, and the **PCI/PCI-X** bus interface.

General-purpose I/O standards such as 3.3-, 2.5-, 1.8-, and 1.5-**LVTTL/LVCMOS** are capable of a typical 167 MHz and 1.2-**LVCMOS** at 100 MHz interfacing frequency with a 10 pF load.



The actual achievable frequency depends on design- and system-specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

### High-Speed I/O Specification

Table 36 lists high-speed I/O timing for Stratix V devices.

**Table 36. High-Speed I/O Specifications for Stratix V Devices <sup>(1)</sup>, <sup>(2)</sup> (Part 1 of 4)**

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4,I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$f_{\text{HCLK\_in}}$ (input clock frequency) True Differential I/O Standards	Clock boost factor $W = 1$ to 40 <sup>(4)</sup>	5	—	800	5	—	800	5	—	625	5	—	525	MHz
$f_{\text{HCLK\_in}}$ (input clock frequency) Single Ended I/O Standards <sup>(3)</sup>	Clock boost factor $W = 1$ to 40 <sup>(4)</sup>	5	—	800	5	—	800	5	—	625	5	—	525	MHz
$f_{\text{HCLK\_in}}$ (input clock frequency) Single Ended I/O Standards	Clock boost factor $W = 1$ to 40 <sup>(4)</sup>	5	—	520	5	—	520	5	—	420	5	—	420	MHz
$f_{\text{HCLK\_OUT}}$ (output clock frequency)	—	5	—	800	5	—	800	5	—	625 <sup>(5)</sup>	5	—	525 <sup>(5)</sup>	MHz



**Table 36. High-Speed I/O Specifications for Stratix V Devices <sup>(1)</sup>, <sup>(2)</sup> (Part 3 of 4)**

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4, I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$t_{DUTY}$	Transmitter output clock duty cycle for both True and Emulated Differential I/O Standards	45	50	55	45	50	55	45	50	55	45	50	55	%
$t_{RISE}$ & $t_{FALL}$	True Differential I/O Standards	—	—	160	—	—	160	—	—	200	—	—	200	ps
	Emulated Differential I/O Standards with three external output resistor networks	—	—	250	—	—	250	—	—	250	—	—	300	ps
TCCS	True Differential I/O Standards	—	—	150	—	—	150	—	—	150	—	—	150	ps
	Emulated Differential I/O Standards	—	—	300	—	—	300	—	—	300	—	—	300	ps
<b>Receiver</b>														
True Differential I/O Standards - $f_{HSDRDPA}$ (data rate)	SERDES factor J = 3 to 10 <sup>(11)</sup> , <sup>(12)</sup> , <sup>(13)</sup> , <sup>(14)</sup> , <sup>(15)</sup> , <sup>(16)</sup>	150	—	1434	150	—	1434	150	—	1250	150	—	1050	Mbps
	SERDES factor J $\geq 4$	150	—	1600	150	—	1600	150	—	1600	150	—	1250	Mbps
	LVDS RX with DPA <sup>(12)</sup> , <sup>(14)</sup> , <sup>(15)</sup> , <sup>(16)</sup>	150	—	1600	150	—	1600	150	—	1600	150	—	1250	Mbps
	SERDES factor J = 2, uses DDR Registers	<sup>(6)</sup>	—	<sup>(7)</sup>	<sup>(6)</sup>	—	<sup>(7)</sup>	<sup>(6)</sup>	—	<sup>(7)</sup>	<sup>(6)</sup>	—	<sup>(7)</sup>	Mbps
	SERDES factor J = 1, uses SDR Register	<sup>(6)</sup>	—	<sup>(7)</sup>	<sup>(6)</sup>	—	<sup>(7)</sup>	<sup>(6)</sup>	—	<sup>(7)</sup>	<sup>(6)</sup>	—	<sup>(7)</sup>	Mbps

**Table 36. High-Speed I/O Specifications for Stratix V Devices <sup>(1), (2)</sup> (Part 4 of 4)**

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4, I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f <sub>HSDR</sub> (data rate)	SERDES factor J = 3 to 10	(6)	—	(8)	(6)	—	(8)	(6)	—	(8)	(6)	—	(8)	Mbps
	SERDES factor J = 2, uses DDR Registers	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	Mbps
	SERDES factor J = 1, uses SDR Register	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	Mbps
<b>DPA Mode</b>														
DPA run length	—	—	—	1000 0	—	—	1000 0	—	—	1000 0	—	—	1000 0	UI
<b>Soft CDR mode</b>														
Soft-CDR PPM tolerance	—	—	—	300	—	—	300	—	—	300	—	—	300	± PPM
<b>Non DPA Mode</b>														
Sampling Window	—	—	—	300	—	—	300	—	—	300	—	—	300	ps

**Notes to Table 36:**

- (1) When J = 3 to 10, use the serializer/deserializer (SERDES) block.
- (2) When J = 1 or 2, bypass the SERDES block.
- (3) This only applies to DPA and soft-CDR modes.
- (4) Clock Boost Factor (W) is the ratio between the input data rate to the input clock rate.
- (5) This is achieved by using the **LVDS** clock network.
- (6) The minimum specification depends on the clock source (for example, the PLL and clock pin) and the clock routing resource (global, regional, or local) that you use. The I/O differential buffer and input register do not have a minimum toggle rate.
- (7) The maximum ideal frequency is the SERDES factor (J) x the PLL maximum output frequency (f<sub>OUT</sub>) provided you can close the design timing and the signal integrity simulation is clean.
- (8) You can estimate the achievable maximum data rate for non-DPA mode by performing link timing closure analysis. You must consider the board skew margin, transmitter delay margin, and receiver sampling margin to determine the maximum data rate supported.
- (9) If the receiver with DPA enabled and transmitter are using shared PLLs, the minimum data rate is 150 Mbps.
- (10) You must calculate the leftover timing margin in the receiver by performing link timing closure analysis. You must consider the board skew margin, transmitter channel-to-channel skew, and receiver sampling margin to determine leftover timing margin.
- (11) The F<sub>MAX</sub> specification is based on the fast clock used for serial data. The interface F<sub>MAX</sub> is also dependent on the parallel clock domain which is design-dependent and requires timing analysis.
- (12) Stratix V RX LVDS will need DPA. For Stratix V TX LVDS, the receiver side component must have DPA.
- (13) Stratix V LVDS serialization and de-serialization factor needs to be x4 and above.
- (14) Requires package skew compensation with PCB trace length.
- (15) Do not mix single-ended I/O buffer within LVDS I/O bank.
- (16) Chip-to-chip communication only with a maximum load of 5 pF.
- (17) When using True LVDS RX channels for emulated LVDS TX channel, only serialization factors 1 and 2 are supported.

**Table 42. Memory Output Clock Jitter Specification for Stratix V Devices <sup>(1)</sup>, (Part 2 of 2) <sup>(2)</sup>, <sup>(3)</sup>**

Clock Network	Parameter	Symbol	C1		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4,I4		Unit
			Min	Max	Min	Max	Min	Max	Min	Max	
PHY Clock	Clock period jitter	$t_{JIT(per)}$	-25	25	-25	25	-30	30	-35	35	ps
	Cycle-to-cycle period jitter	$t_{JIT(cc)}$	-50	50	-50	50	-60	60	-70	70	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-37.5	37.5	-37.5	37.5	-45	45	-56	56	ps

**Notes to Table 42:**

- (1) The clock jitter specification applies to the memory output clock pins generated using differential signal-splitter and DDIO circuits clocked by a PLL output routed on a PHY, regional, or global clock network as specified. Altera recommends using PHY clock networks whenever possible.
- (2) The clock jitter specification applies to the memory output clock pins clocked by an integer PLL.
- (3) The memory output clock jitter is applicable when an input jitter of 30 ps peak-to-peak is applied with bit error rate (BER) -12, equivalent to 14 sigma.

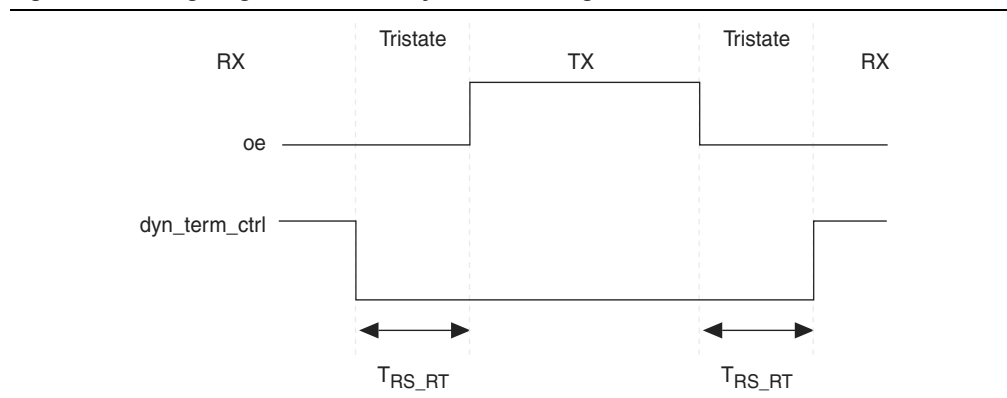
**OCT Calibration Block Specifications**

Table 43 lists the OCT calibration block specifications for Stratix V devices.

**Table 43. OCT Calibration Block Specifications for Stratix V Devices**

Symbol	Description	Min	Typ	Max	Unit
OCTUSRCLK	Clock required by the OCT calibration blocks	—	—	20	MHz
$T_{OCTCAL}$	Number of OCTUSRCLK clock cycles required for OCT $R_S/R_T$ calibration	—	1000	—	Cycles
$T_{OCTSHIFT}$	Number of OCTUSRCLK clock cycles required for the OCT code to shift out	—	32	—	Cycles
$T_{RS\_RT}$	Time required between the <code>dyn_term_ctrl</code> and <code>oe</code> signal transitions in a bidirectional I/O buffer to dynamically switch between OCT $R_S$ and $R_T$ (Figure 10)	—	2.5	—	ns

Figure 10 shows the timing diagram for the `oe` and `dyn_term_ctrl` signals.

**Figure 10. Timing Diagram for `oe` and `dyn_term_ctrl` Signals**

**Table 46. JTAG Timing Parameters and Values for Stratix V Devices**

Symbol	Description	Min	Max	Unit
$t_{JPH}$	JTAG port hold time	5	—	ns
$t_{JPCO}$	JTAG port clock to output	—	11 <sup>(1)</sup>	ns
$t_{JPZX}$	JTAG port high impedance to valid output	—	14 <sup>(1)</sup>	ns
$t_{JPXZ}$	JTAG port valid output to high impedance	—	14 <sup>(1)</sup>	ns

**Notes to Table 46:**

- (1) A 1 ns adder is required for each  $V_{CCIO}$  voltage step down from 3.0 V. For example,  $t_{JPCO}$  = 12 ns if  $V_{CCIO}$  of the TDO I/O bank = 2.5 V, or 13 ns if it equals 1.8 V.
- (2) The minimum TCK clock period is 167 ns if VCCBAT is within the range 1.2V-1.5V when you perform the volatile key programming.

## Raw Binary File Size

For the POR delay specification, refer to the “POR Delay Specification” section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices”.

Table 47 lists the uncompressed raw binary file (.rbf) sizes for Stratix V devices.

**Table 47. Uncompressed .rbf Sizes for Stratix V Devices**

Family	Device	Package	Configuration .rbf Size (bits)	IOCSR .rbf Size (bits) <sup>(4), (5)</sup>
Stratix V GX	5SGXA3	H35, F40, F35 <sup>(2)</sup>	213,798,880	562,392
		H29, F35 <sup>(3)</sup>	137,598,880	564,504
	5SGXA4	—	213,798,880	563,672
	5SGXA5	—	269,979,008	562,392
	5SGXA7	—	269,979,008	562,392
	5SGXA9	—	342,742,976	700,888
	5SGXAB	—	342,742,976	700,888
	5SGXB5	—	270,528,640	584,344
	5SGXB6	—	270,528,640	584,344
	5SGXB9	—	342,742,976	700,888
	5SGXBB	—	342,742,976	700,888
Stratix V GT	5SGTC5	—	269,979,008	562,392
	5SGTC7	—	269,979,008	562,392
Stratix V GS	5SGSD3	—	137,598,880	564,504
	5SGSD4	F1517	213,798,880	563,672
		—	137,598,880	564,504
	5SGSD5	—	213,798,880	563,672
	5SGSD6	—	293,441,888	565,528
	5SGSD8	—	293,441,888	565,528



Table 50 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA [] ratio is 1.

**Table 50. FPP Timing Parameters for Stratix V Devices <sup>(1)</sup>**

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CF2CD</sub>	nCONFIG low to CONF_DONE low	—	600	ns
t <sub>CF2ST0</sub>	nCONFIG low to nSTATUS low	—	600	ns
t <sub>CFG</sub>	nCONFIG low pulse width	2	—	μs
t <sub>STATUS</sub>	nSTATUS low pulse width	268	1,506 <sup>(2)</sup>	μs
t <sub>CF2ST1</sub>	nCONFIG high to nSTATUS high	—	1,506 <sup>(3)</sup>	μs
t <sub>CF2CK</sub> <sup>(6)</sup>	nCONFIG high to first rising edge on DCLK	1,506	—	μs
t <sub>ST2CK</sub> <sup>(6)</sup>	nSTATUS high to first rising edge of DCLK	2	—	μs
t <sub>DSU</sub>	DATA [] setup time before rising edge on DCLK	5.5	—	ns
t <sub>DH</sub>	DATA [] hold time after rising edge on DCLK	0	—	ns
t <sub>CH</sub>	DCLK high time	$0.45 \times 1/f_{\text{MAX}}$	—	s
t <sub>CL</sub>	DCLK low time	$0.45 \times 1/f_{\text{MAX}}$	—	s
t <sub>CLK</sub>	DCLK period	$1/f_{\text{MAX}}$	—	s
f <sub>MAX</sub>	DCLK frequency (FPP $\times 8/\times 16$ )	—	125	MHz
	DCLK frequency (FPP $\times 32$ )	—	100	MHz
t <sub>CD2UM</sub>	CONF_DONE high to user mode <sup>(4)</sup>	175	437	μs
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	4 $\times$ maximum DCLK period	—	—
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	t <sub>CD2CU</sub> + (8576 $\times$ CLKUSR period) <sup>(5)</sup>	—	—

**Notes to Table 50:**

- (1) Use these timing parameters when the decompression and design security features are disabled.
- (2) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.
- (4) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.
- (5) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.
- (6) If nSTATUS is monitored, follow the t<sub>ST2CK</sub> specification. If nSTATUS is not monitored, follow the t<sub>CF2CK</sub> specification.

### FPP Configuration Timing when DCLK-to-DATA [] > 1

Figure 13 shows the timing waveform for FPP configuration when using a MAX II device, MAX V device, or microprocessor as an external host. This waveform shows timing when the DCLK-to-DATA [] ratio is more than 1.

## Active Serial Configuration Timing

Table 52 lists the DCLK frequency specification in the AS configuration scheme.

**Table 52. DCLK Frequency Specification in the AS Configuration Scheme <sup>(1), (2)</sup>**

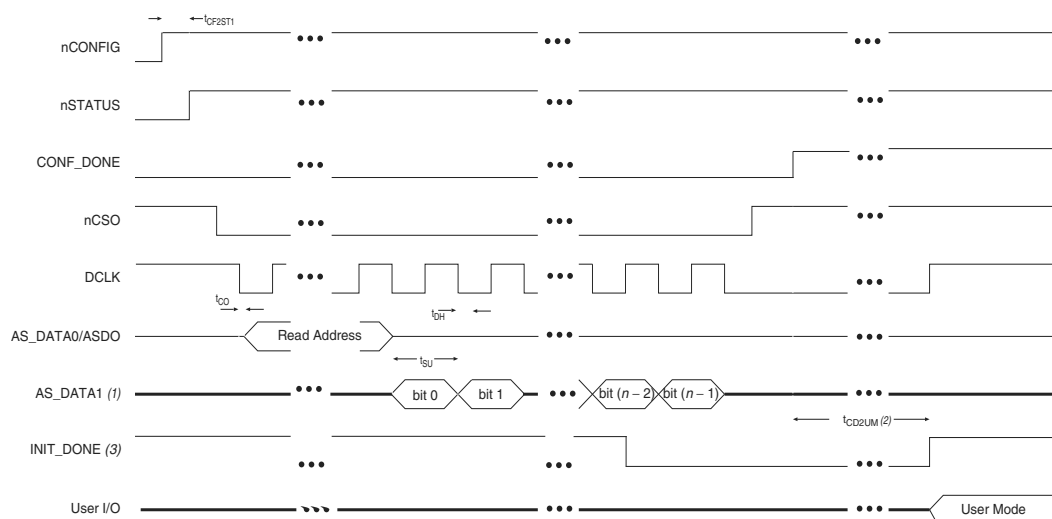
Minimum	Typical	Maximum	Unit
5.3	7.9	12.5	MHz
10.6	15.7	25.0	MHz
21.3	31.4	50.0	MHz
42.6	62.9	100.0	MHz

**Notes to Table 52:**

- (1) This applies to the DCLK frequency specification when using the internal oscillator as the configuration clock source.
- (2) The AS multi-device configuration scheme does not support DCLK frequency of 100 MHz.

Figure 14 shows the single-device configuration setup for an AS ×1 mode.

**Figure 14. AS Configuration Timing**



**Notes to Figure 14:**

- (1) If you are using AS ×4 mode, this signal represents the AS\_DATA [3 : 0] and EPCQ sends in 4-bits of data for each DCLK cycle.
- (2) The initialization clock can be from internal oscillator or CLKUSR pin.
- (3) After the option bit to enable the INIT\_DONE pin is configured into the device, the INIT\_DONE goes low.

Table 53 lists the timing parameters for AS ×1 and AS ×4 configurations in Stratix V devices.

**Table 53. AS Timing Parameters for AS ×1 and AS ×4 Configurations in Stratix V Devices <sup>(1), (2)</sup> (Part 1 of 2)**

Symbol	Parameter	Minimum	Maximum	Units
$t_{CO}$	DCLK falling edge to AS_DATA0/ASDO output	—	2	ns
$t_{SU}$	Data setup time before falling edge on DCLK	1.5	—	ns
$t_H$	Data hold time after falling edge on DCLK	0	—	ns

**Table 53. AS Timing Parameters for AS ×1 and AS ×4 Configurations in Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 2)**

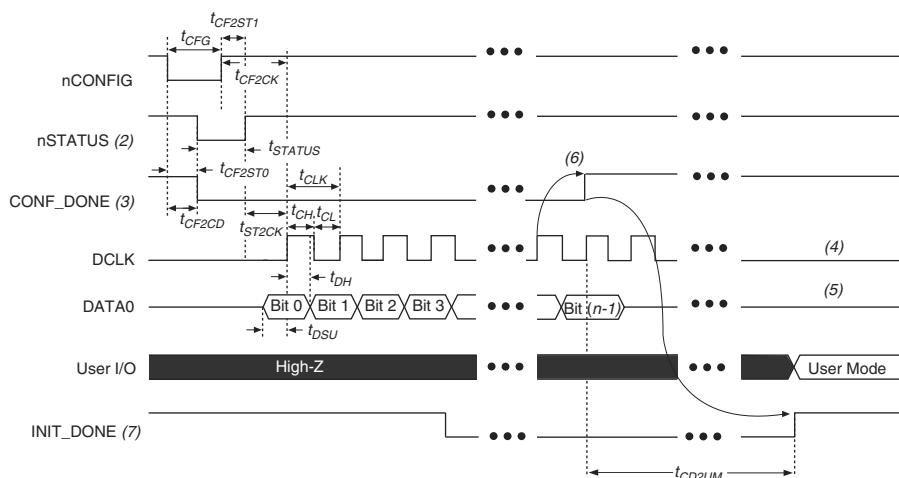
Symbol	Parameter	Minimum	Maximum	Units
$t_{CD2UM}$	CONF_DONE high to user mode <sup>(3)</sup>	175	437	μs
$t_{CD2CU}$	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	—	—
$t_{CD2UMC}$	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU} + (8576 \times \text{CLKUSR period})$	—	—

**Notes to Table 53:**

- (1) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.
- (2)  $t_{CF2CD}$ ,  $t_{CF2ST0}$ ,  $t_{CFG}$ ,  $t_{STATUS}$ , and  $t_{CF2ST1}$  timing parameters are identical to the timing parameters for PS mode listed in Table 54 on page 63.
- (3) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on this pin, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.

## Passive Serial Configuration Timing

Figure 15 shows the timing waveform for a passive serial (PS) configuration when using a MAX II device, MAX V device, or microprocessor as an external host.

**Figure 15. PS Configuration Timing Waveform <sup>(1)</sup>****Notes to Figure 15:**

- (1) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF\_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (2) After power-up, the Stratix V device holds nSTATUS low for the time of the POR delay.
- (3) After power-up, before and during configuration, CONF\_DONE is low.
- (4) Do not leave DCLK floating after configuration. You can drive it high or low, whichever is more convenient.
- (5) DATA0 is available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings in the **Device and Pins Option**.
- (6) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF\_DONE is released high after the Stratix V device receives all the configuration data successfully. After CONF\_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (7) After the option bit to enable the INIT\_DONE pin is configured into the device, the INIT\_DONE goes low.



Table 54 lists the PS configuration timing parameters for Stratix V devices.

**Table 54. PS Timing Parameters for Stratix V Devices**

Symbol	Parameter	Minimum	Maximum	Units
$t_{CF2CD}$	nCONFIG low to CONF_DONE low	—	600	ns
$t_{CF2ST0}$	nCONFIG low to nSTATUS low	—	600	ns
$t_{CFG}$	nCONFIG low pulse width	2	—	$\mu$ s
$t_{STATUS}$	nSTATUS low pulse width	268	1,506 <sup>(1)</sup>	$\mu$ s
$t_{CF2ST1}$	nCONFIG high to nSTATUS high	—	1,506 <sup>(2)</sup>	$\mu$ s
$t_{CF2CK}$ <sup>(5)</sup>	nCONFIG high to first rising edge on DCLK	1,506	—	$\mu$ s
$t_{ST2CK}$ <sup>(5)</sup>	nSTATUS high to first rising edge of DCLK	2	—	$\mu$ s
$t_{DSU}$	DATA [] setup time before rising edge on DCLK	5.5	—	ns
$t_{DH}$	DATA [] hold time after rising edge on DCLK	0	—	ns
$t_{CH}$	DCLK high time	$0.45 \times 1/f_{MAX}$	—	s
$t_{CL}$	DCLK low time	$0.45 \times 1/f_{MAX}$	—	s
$t_{CLK}$	DCLK period	$1/f_{MAX}$	—	s
$f_{MAX}$	DCLK frequency	—	125	MHz
$t_{CD2UM}$	CONF_DONE high to user mode <sup>(3)</sup>	175	437	$\mu$ s
$t_{CD2CU}$	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	—	—
$t_{CD2UMC}$	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU} + (8576 \times \text{CLKUSR period})$ <sup>(4)</sup>	—	—

**Notes to Table 54:**

- (1) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (2) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.
- (3) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the “Initialization” section.
- (5) If nSTATUS is monitored, follow the  $t_{ST2CK}$  specification. If nSTATUS is not monitored, follow the  $t_{CF2CK}$  specification.

## Initialization

Table 55 lists the initialization clock source option, the applicable configuration schemes, and the maximum frequency.

**Table 55. Initialization Clock Source Option and the Maximum Frequency**

Initialization Clock Source	Configuration Schemes	Maximum Frequency	Minimum Number of Clock Cycles <sup>(1)</sup>
Internal Oscillator	AS, PS, FPP	12.5 MHz	8576
CLKUSR	AS, PS, FPP <sup>(2)</sup>	125 MHz	
DCLK	PS, FPP	125 MHz	

**Notes to Table 55:**

- (1) The minimum number of clock cycles required for device initialization.
- (2) To enable CLKUSR as the initialization clock source, turn on the **Enable user-supplied start-up clock (CLKUSR)** option in the Quartus II software from the **General** panel of the **Device and Pin Options** dialog box.

**Table 58. IOE Programmable Delay for Stratix V Devices (Part 2 of 2)**

Parameter (1)	Available Settings	Min Offset (2)	Fast Model		Slow Model							
			Industrial	Commercial	C1	C2	C3	C4	I2	I3, I3YY	I4	Unit
D3	8	0	1.587	1.699	2.793	2.793	2.992	3.192	2.811	3.047	3.257	ns
D4	64	0	0.464	0.492	0.838	0.838	0.924	1.011	0.843	0.920	1.006	ns
D5	64	0	0.464	0.493	0.838	0.838	0.924	1.011	0.844	0.921	1.006	ns
D6	32	0	0.229	0.244	0.415	0.415	0.458	0.503	0.418	0.456	0.499	ns

**Notes to Table 58:**

- (1) You can set this value in the Quartus II software by selecting **D1**, **D2**, **D3**, **D5**, and **D6** in the **Assignment Name** column of **Assignment Editor**.
- (2) Minimum offset does not include the intrinsic delay.

## Programmable Output Buffer Delay

Table 59 lists the delay chain settings that control the rising and falling edge delays of the output buffer. The default delay is 0 ps.

**Table 59. Programmable Output Buffer Delay for Stratix V Devices (1)**

Symbol	Parameter	Typical	Unit
D <sub>OUTBUF</sub>	Rising and/or falling edge delay	0 (default)	ps
		25	ps
		50	ps
		75	ps

**Note to Table 59:**

- (1) You can set the programmable output buffer delay in the Quartus II software by setting the **Output Buffer Delay Control** assignment to either positive, negative, or both edges, with the specific values stated here (in ps) for the **Output Buffer Delay** assignment.

## Glossary

Table 60 lists the glossary for this chapter.

**Table 60. Glossary (Part 1 of 4)**

Letter	Subject	Definitions
A	—	—
B		
C		
D	—	—
E	—	—
F	f <sub>HCLK</sub>	Left and right PLL input clock frequency.
	f <sub>HSDR</sub>	High-speed I/O block—Maximum and minimum <b>LVDS</b> data transfer rate (f <sub>HSDR</sub> = 1/TUI), non-DPA.
	f <sub>HSDRDPA</sub>	High-speed I/O block—Maximum and minimum <b>LVDS</b> data transfer rate (f <sub>HSDRDPA</sub> = 1/TUI), DPA.

Table 60. Glossary (Part 2 of 4)

Letter	Subject	Definitions
G H I	—	—
J	JTAG Timing Specifications	<p>High-speed I/O block—Deserialization factor (width of parallel data bus).</p> <p>JTAG Timing Specifications:</p> 
K L M N O	—	—
P	PLL Specifications	<p><b>Diagram of PLL Specifications <sup>(1)</sup></b></p>  <p><b>Note:</b> (1) Core Clock can only be fed by dedicated clock input pins or PLL outputs.</p>
Q	—	—
R	R <sub>L</sub>	Receiver differential input discrete resistor (external to the Stratix V device).

## Document Revision History

Table 61 lists the revision history for this chapter.

**Table 61. Document Revision History (Part 1 of 3)**

Date	Version	Changes
June 2018	3.9	<ul style="list-style-type: none"> <li>■ Added the “Stratix V Device Overshoot Duration” figure.</li> </ul>
April 2017	3.8	<ul style="list-style-type: none"> <li>■ Added a footnote to the “High-Speed I/O Specifications for Stratix V Devices” table.</li> <li>■ Changed the minimum value for <math>t_{CD2UMC}</math> in the “PS Timing Parameters for Stratix V Devices” table.</li> <li>■ Changed the condition for <math>100\text{-}\Omega</math> <math>R_D</math> in the “OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices” table.</li> <li>■ Changed the minimum value for <math>t_{CD2UMC}</math> in the “AS Timing Parameters for AS ‘1 and AS ‘4 Configurations in Stratix V Devices” table</li> <li>■ Changed the minimum value for <math>t_{CD2UMC}</math> in the “FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is &gt;1” table.</li> <li>■ Changed the minimum value for <math>t_{CD2UMC}</math> in the “FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is &gt;1” table.</li> <li>■ Changed the minimum number of clock cycles value in the “Initialization Clock Source Option and the Maximum Frequency” table.</li> </ul>
June 2016	3.7	<ul style="list-style-type: none"> <li>■ Added the <math>V_{ID}</math> minimum specification for LVPECL in the “Differential I/O Standard Specifications for Stratix V Devices” table</li> <li>■ Added the <math>I_{OUT}</math> specification to the “Absolute Maximum Ratings for Stratix V Devices” table.</li> </ul>
December 2015	3.6	<ul style="list-style-type: none"> <li>■ Added a footnote to the “High-Speed I/O Specifications for Stratix V Devices” table.</li> </ul>
December 2015	3.5	<ul style="list-style-type: none"> <li>■ Changed the transmitter, receiver, and ATX PLL data rate specifications in the “Transceiver Specifications for Stratix V GX and GS Devices” table.</li> <li>■ Changed the configuration .rbf sizes in the “Uncompressed .rbf Sizes for Stratix V Devices” table.</li> </ul>
July 2015	3.4	<ul style="list-style-type: none"> <li>■ Changed the data rate specification for transceiver speed grade 3 in the following tables:               <ul style="list-style-type: none"> <li>■ “Transceiver Specifications for Stratix V GX and GS Devices”</li> <li>■ “Stratix V Standard PCS Approximate Maximum Date Rate”</li> <li>■ “Stratix V 10G PCS Approximate Maximum Data Rate”</li> </ul> </li> <li>■ Changed the conditions for reference clock rise and fall time, and added a note to the “Transceiver Specifications for Stratix V GX and GS Devices” table.</li> <li>■ Added a note to the “Minimum differential eye opening at receiver serial input pins” specification in the “Transceiver Specifications for Stratix V GX and GS Devices” table.</li> <li>■ Changed the <math>t_{CO}</math> maximum value in the “AS Timing Parameters for AS ‘1 and AS ‘4 Configurations in Stratix V Devices” table.</li> <li>■ Removed the CDR ppm tolerance specification from the “Transceiver Specifications for Stratix V GX and GS Devices” table.</li> </ul>

**Table 61. Document Revision History (Part 2 of 3)**

Date	Version	Changes
November 2014	3.3	<ul style="list-style-type: none"> <li>■ Added the I3YY speed grade and changed the data rates for the GX channel in Table 1.</li> <li>■ Added the I3YY speed grade to the <math>V_{CC}</math> description in Table 6.</li> <li>■ Added the I3YY speed grade to <math>V_{CCHIP\_L}</math>, <math>V_{CCHIP\_R}</math>, <math>V_{CCHSSI\_L}</math>, and <math>V_{CCHSSI\_R}</math> descriptions in Table 7.</li> <li>■ Added 240-<math>\Omega</math> to Table 11.</li> <li>■ Changed CDR PPM tolerance in Table 23.</li> <li>■ Added additional max data rate for fPLL in Table 23.</li> <li>■ Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 25.</li> <li>■ Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 26.</li> <li>■ Changed CDR PPM tolerance in Table 28.</li> <li>■ Added additional max data rate for fPLL in Table 28.</li> <li>■ Changed the mode descriptions for MLAB and M20K in Table 33.</li> <li>■ Changed the Max value of <math>f_{HCLK\_OUT}</math> for the C2, C2L, I2, I2L speed grades in Table 36.</li> <li>■ Changed the frequency ranges for C1 and C2 in Table 39.</li> <li>■ Changed the .rbf file sizes for 5SGSD6 and 5SGSD8 in Table 47.</li> <li>■ Added note about nSTATUS to Table 50, Table 51, Table 54.</li> <li>■ Changed the available settings in Table 58.</li> <li>■ Changed the note in “Periphery Performance”.</li> <li>■ Updated the “I/O Standard Specifications” section.</li> <li>■ Updated the “Raw Binary File Size” section.</li> <li>■ Updated the receiver voltage input range in Table 22.</li> <li>■ Updated the max frequency for the LVDS clock network in Table 36.</li> <li>■ Updated the DCLK note to Figure 11.</li> <li>■ Updated Table 23 <math>VO_{CM}</math> (DC Coupled) condition.</li> <li>■ Updated Table 6 and Table 7.</li> <li>■ Added the DCLK specification to Table 55.</li> <li>■ Updated the notes for Table 47.</li> <li>■ Updated the list of parameters for Table 56.</li> </ul>
November 2013	3.2	■ Updated Table 28
November 2013	3.1	■ Updated Table 33
November 2013	3.0	■ Updated Table 23 and Table 28
October 2013	2.9	■ Updated the “Transceiver Characterization” section
October 2013	2.8	<ul style="list-style-type: none"> <li>■ Updated Table 3, Table 12, Table 14, Table 19, Table 20, Table 23, Table 24, Table 28, Table 30, Table 31, Table 32, Table 33, Table 36, Table 39, Table 40, Table 41, Table 42, Table 47, Table 53, Table 58, and Table 59</li> <li>■ Added Figure 1 and Figure 3</li> <li>■ Added the “Transceiver Characterization” section</li> <li>■ Removed all “Preliminary” designations.</li> </ul>